



FEATURES

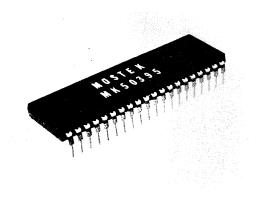
- □ Single power supply
- Schmitt Trigger on the count input
 Six decades of synchronous up/down
- Six decades of synchronous i counting
- □ Look-ahead carry or borrow
- Loadable counter
- □ Loadable compare register with comparator output
- Multiplexed BCD and seven-segment outputs
- Internal scan oscillator
- Direct LED segment drive
- Interfaces directly with CMOS logic
- Leading zero blanking
- MK 50396 programmed to count time: 99 hrs. 59 min. 59 sec.
- MK 50397 programmed to count time: 59 min. 59 sec. 99/100 sec.

DESCRIPTION

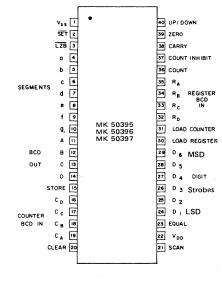
The MK 50395 is an ion-implanted, Pchannel MOS six-decade synchronous up/down counter/display driver with compare register and storage latches. The counter as well as the register can be loaded digit-by-digit with BCD data. The counter has an asynchronous-clear function.

Scanning is controlled by the scan oscillator input which is self-oscillating or can be driven by an external signal. The six-decade register is constantly compared to the state of the six-decade counter and when both the register and the counter have the same content, an EQUAL signal is generated. The contents of the counter can be transferred into the 6-digit latch which is then multiplexed from MSD to LSD in BCD and 7-segment format to the output. The seven-segment decoder incorporates a leading-zero blanking circuit which can be disabled by an external signal. This device is intended to interface directly with the standard CMOS logic families.

The MK 50396 and MK 50397 operate identically to the MK 50395 except that two digits in each were reprogrammed to provide divide by six circuitry instead of divide by ten. The MK 50396 is well suited for industrial timer applications while the MK 50397 is best suited for stop watch or realtime computer clock applications.



PIN CONNECTIONS FIGURE 1



V COUNTER DISPLAY DECODERS



SIX-DECADE COUNTER, LATCH

The six-decade counter is synchronously incremented or decremented on the positive edge of the count input signal. A Schmitt trigger on this input provides hysteresis for protection against both a noisy environment and double triggering due to a slow rising edge at the count input.

The count inhibit can be changed in coincidence with the positive transition of the count input; the count input is inhibited when the count inhibit is high.

The counter will increment when the up/down input is high (VSS) and will decrement when the up/down input is low. The up/down input can be changed 0.75 μ s prior to the positive transition of the count input.

The clear input is asynchronous and will reset all decades to zero when brought high but does not affect the six-digit latch or the scan counter.

As long as the store input is low, data is continuously transferred from the counter to the display. Data in the counter will be latched and displayed when the store input is high. Store can be changed in coincidence with the positive transition of the count input.

The counter is loaded digit-by-digit corresponding to the digit strobe outputs. BCD thumb wheel switches with four diodes per decade connected between the digit strobe outputs and the BCD inputs is one method to supply BCD data for loading the counter decades.

The load counter pulse must be at VSs 2 microseconds prior to the positive transition of the digit strobe of the digit to be loaded. The load counter pulse may be removed after the positive transition of the digit strobe since the chip internally latches this signal. The BCD data to be loaded must be valid through the negative transition of the digit strobe.

INPUTS, OUTPUTS

The seven segment outputs are open drain and capable of sourcing 10mA average current per segment over one digit cycle. Segments are on when at VSs. The Carry, Equal, Zero, BCD and digit strobe outputs are push-pull and are on when at VSs. All inputs except Counter BCD, Register BCD, and SCAN inputs are high-impedance CMOS compatible.

Three basic outputs originate from the counter: Zero output, Equal output, and Carry output. Each output goes high on the positive- (VSS) going edge of the count input under the following conditions:

The Zero output goes high for one count period when all decades contain zero. During a load counter operation the zero output is inhibited.

The Equal output goes high for one count period when the contents of the counter and compare register are equal. The equal output is inhibited by a load counter or load register operation, which lasts until the next interdigit blanking period following a negative transition of Load Counter or Load Register. Course and the second

The Carry output goes high with the leading edge of the count input at the count of 000000 when counting up or at 999999* when counting down and goes low with the negative going edge of the same count input.

A count frequency of 1 MHz can be achieved if the Equal output, Zero output and Carry output are not used. These outputs do not respond at this frequency due to their output delay, as illustrated on the timing diagram, Figure 3.

SIX-DECADE COMPARE REGISTER

The register is loaded identically as described in the load counter paragraph. The register may be loaded independently of the counter. However, the Clear input will not remove the register contents. Contents of the register are not displayed by the BCD or seven-segment outputs.

BCD & SEVEN-SEGMENT OUTPUTS

BCD or seven-segment outputs are available. Digit strobes are decoded internally by a divide-by-six Johnson counter. This counter scans from MSD to LSD. By bringing the SET input low, this counter will be forced to the MSD decade count. During this time, the segment outputs are blanked to protect against display burn out.

BCD outputs are valid for MSD when SET is low. Applying Vss to SET allows normal scan to resume. Digit 6 output is active (Vss) until the next scan clock pulse brings up the digit 5 output.

The segment outputs and digit strobes are blanked during the interdigit blanking time. Leading zero blanking affects only the segment outputs. This option is disabled by bringing the LZB input high. Typically, the interdigit blanking time is 5 to 25 microseconds when using the internal scan oscillator.

BCD output data changes at the beginning of the interdigit blanking time. Therefore, the BCD output data is valid when the positive transition of a digit output occurs.

SCAN OSCILLATOR

The MK 50395 has an internal scan oscillator. The frequency of the scan oscillator is determined by an external capacitor between VSS or VDD and the scan input. The wave form present on the scan oscillator input is triangular in the self-oscillate mode.

An external oscillator may also be used to drive the scan input.

In the internal drive mode, the interdigit blanking time will be the sum of the negative dwell period of the external oscillator and the normal self-oscillate blanking time (5 – 25 μ sec). Display brightness can be controlled by the duty cycle of the external scan oscillator.

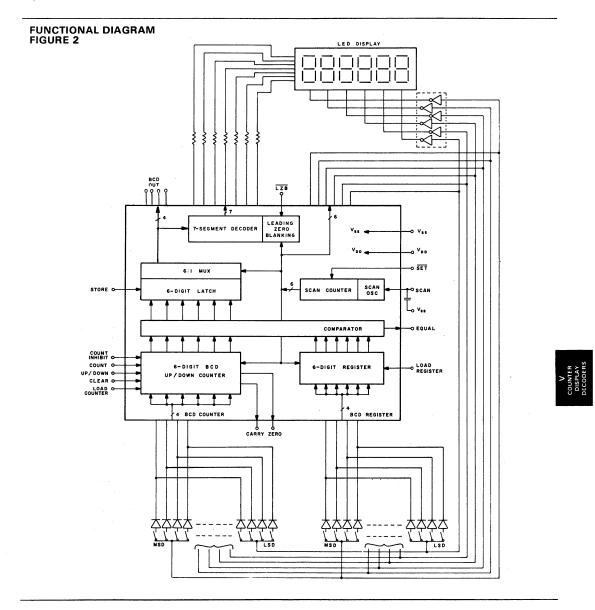
*Carry occurs at 99 59 59 for the MK 50396 and 59 59 99 for the MK 50397





ypically, the scan oscillator will oscillate at the following frequencies with these nominal capacitor values from VSS to the Scan input:

Min	Max	
820pF	1.4kHz	4.8kHz
470pF	2.0kHz	6.8kHz
120pF	7.0kHz	20kHz







SOLUTE MAXIMUM RATINGS

Voltage on Any Terminal Relative to V _{ss}	. +0.3V to -20V
Operating Temperature Range (Ambient).	. 0°C to +70°C
Storage Temperature Range (Ambient).	40°C to +100°C

MAXIMUM OPERATING CONDITIONS

	PARAMETER	MIN	MAX	UNITS	NOTES
TA	Operating Temperature	0	70	°C	
V _{ss}	Supply Voltage (V _{DD} = 0V)	10	15	V	
I _{SS}	Supply Current		30	mA	1
B _v	Break-Down Voltage (Segment only @ 10 μA)		V _{ss} - 26	V	
PD	Power Dissipation		670	mW	2

 $\begin{array}{l} \textbf{ELECTRICAL CHARACTERISTICS} \\ (VDD = 0V, VSS = + 10.0V \ to + 15.0V, \ 0^{\circ}C \leqslant TA \leqslant \ 70^{\circ}C) \end{array}$

Static Operating Conditions

	PARAMETER	MIN	MAX	UNITS	NOTES
VIL	Input Low Voltage, "O"	V _{DD}	20% of Vss	V	
V _{iH}	Input High Voltage, "1"	V _{SS} -1	V _{ss}	V	3
V _{OL}	Output Voltage "0" @ 30μ A		20% of Vss	V	4
V _{он}	Output Voltage "1" @ 1.5 mA	80% of Vss		V	4
I _{он}	Output Current "1" digit strobes segment outputs	3.0 10.0		mA mA	5
I _{SCAN}	Scan Input Pullup Current @ OV		5.5	mA	
I _{SCAN}	Scan Input Pulldown Current @ 15V	2	40	μA	
	SET Input Pullup Current @ 0V	5	60	μA	

NOTES:

S: Iss with inputs and outputs open at 0°C 28mA at 25°C and 25mA at 70°C. This does not include segment current. Total power per segment must be limited so as not to exceed power dissipation of package. (θJA = 100°C/Watt) All outputs loaded. MIN Vik from RA RB RC RD CA CB CC CD inputs is Vss ~2.5V. Those inputs have internal pulldown resistors to VoD. This applies to the push-pull CMOS compatible outputs. Does not include digit strobes or segment outputs. For VOUT = Vss ~2.0 volts. Average value over one digit cycle. 1. 2.

3. 4.

5. 6.





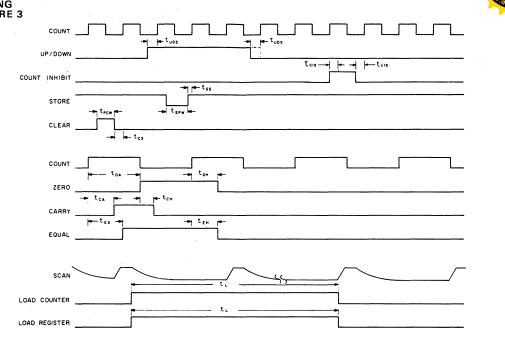
Dynamic Operating Conditions

SYM	PARAMETER	MIN	MAX	UNITS	NOTES
f _{CI}	Count Input Frequency	0	1.00	MHz	7, 8
f _{SI}	Scan Input Frequency	0	20	kHz	
t _{CPW}	Count Pulse Width	400		ns	9
t _{SPW}	Store Pulse Width	2.0		μs	
t _{ss}	Store Setup Time	0		μs	10
t _{CIS}	Count Inhibit Setup Time	0		μs	10
t _{UDS}	Up/Down Setup Time	- 0.75		μs	10
t _{CPW}	Clear Pulse Width	2.0		μs	10
t _{CS}	Clear Setup Time	- 0.5		μs	10
t _{OA}	Zero Access Time		3.0	μs	10
t _{OH}	Zero Hold Time		1.5	μs	10
t _{CA}	Carry Access Time		1.5	μs	10
t _{CH}	Carry Hold Time		0.9	μs	11
t _{EA}	Equal Access Time		2.0	μs	10
t _{EH}	Equal Hold Time	۰.	1.5	μs	10
t	Load Time	1/6 f _{si}			

NOTES:
Measured at 50% duty cycle.
If Carry, Equal, or Zero outputs are used, the count frequency will be limited by their respective output times.
The count pulse width must be greater than the carry access time when using the carry output.
The positive edge of the count input is the t ⁻ 0 reference.
Measured from negative edge of count input.







LOADING COUNTER, REGISTER (1 DIGIT) FIGURE 4

